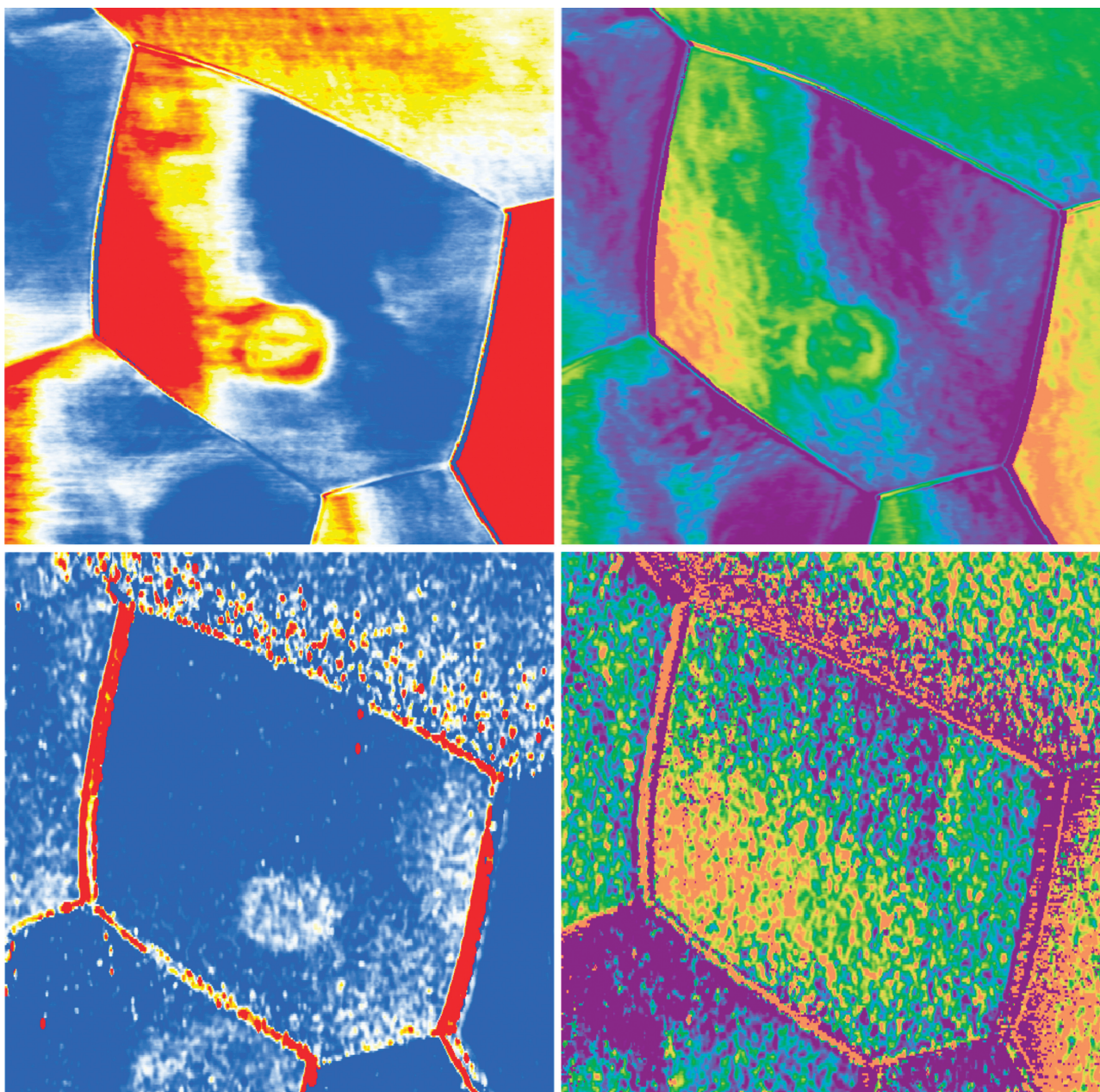


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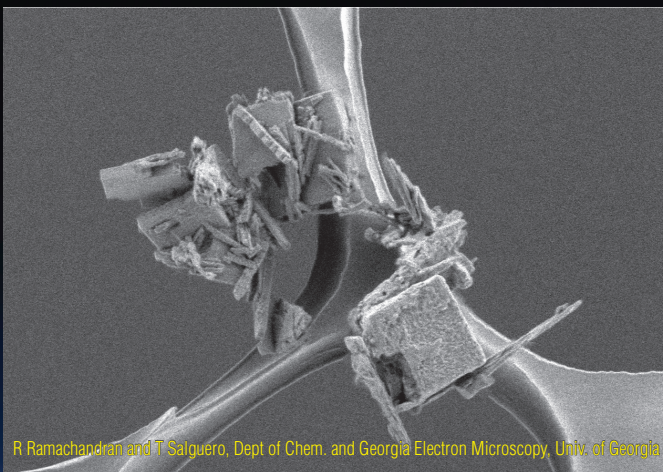
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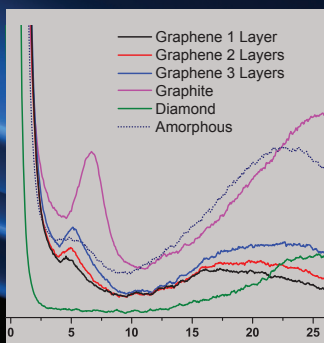
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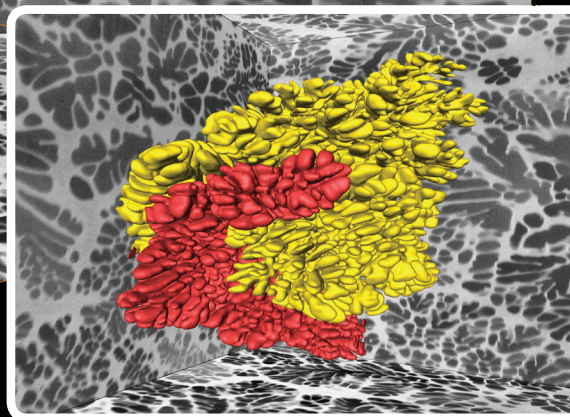
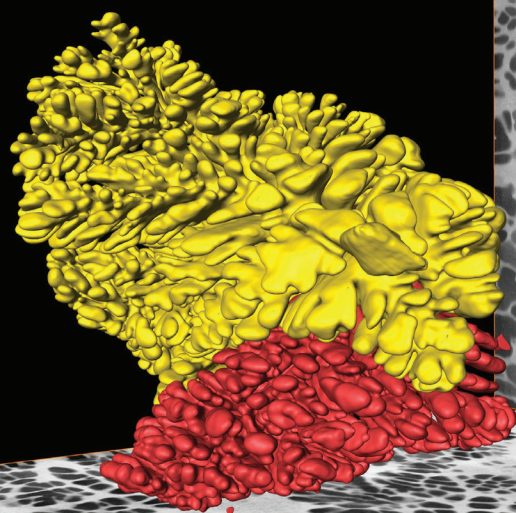
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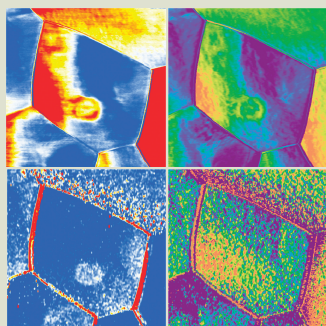
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Scanning thermo-ionic microscopy of polycrystalline ceria at room temperature. Top row: thermomechanical responses. Bottom row: electrochemical responses. Image width = 909 nm.

See article by Esfahani et al.

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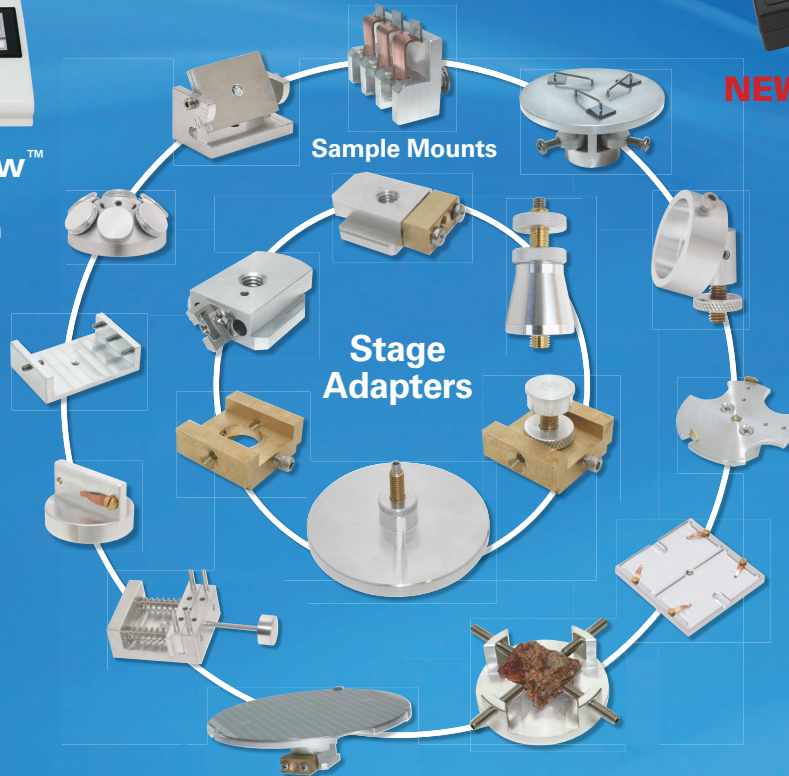
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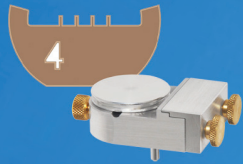
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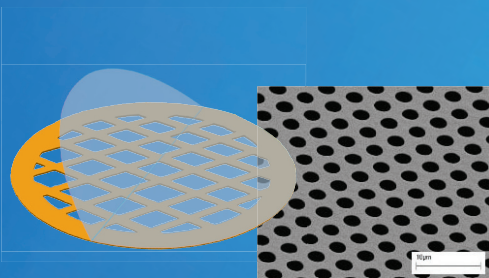
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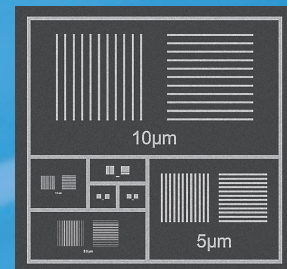
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